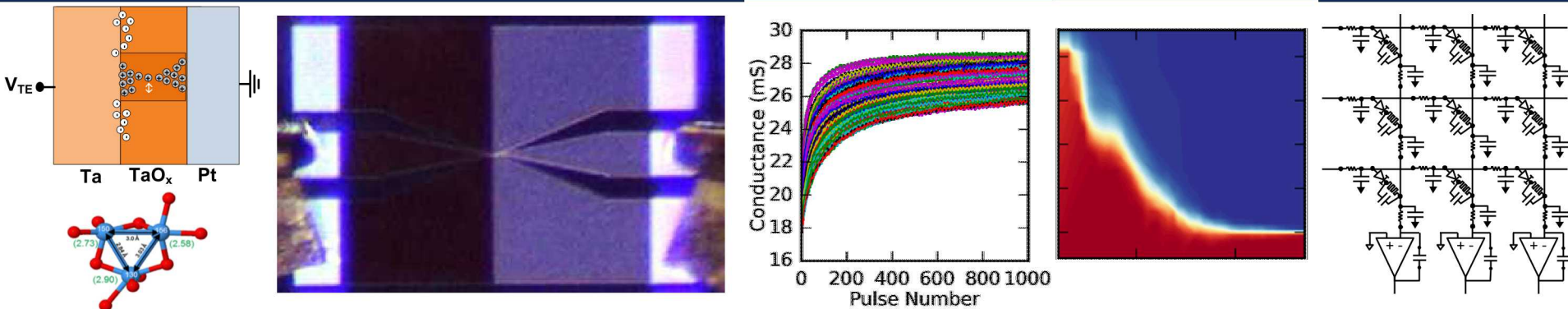


Neuromorphic Computing with Analog Nonvolatile Memory

Matthew J. Marinella
Sandia National Laboratories



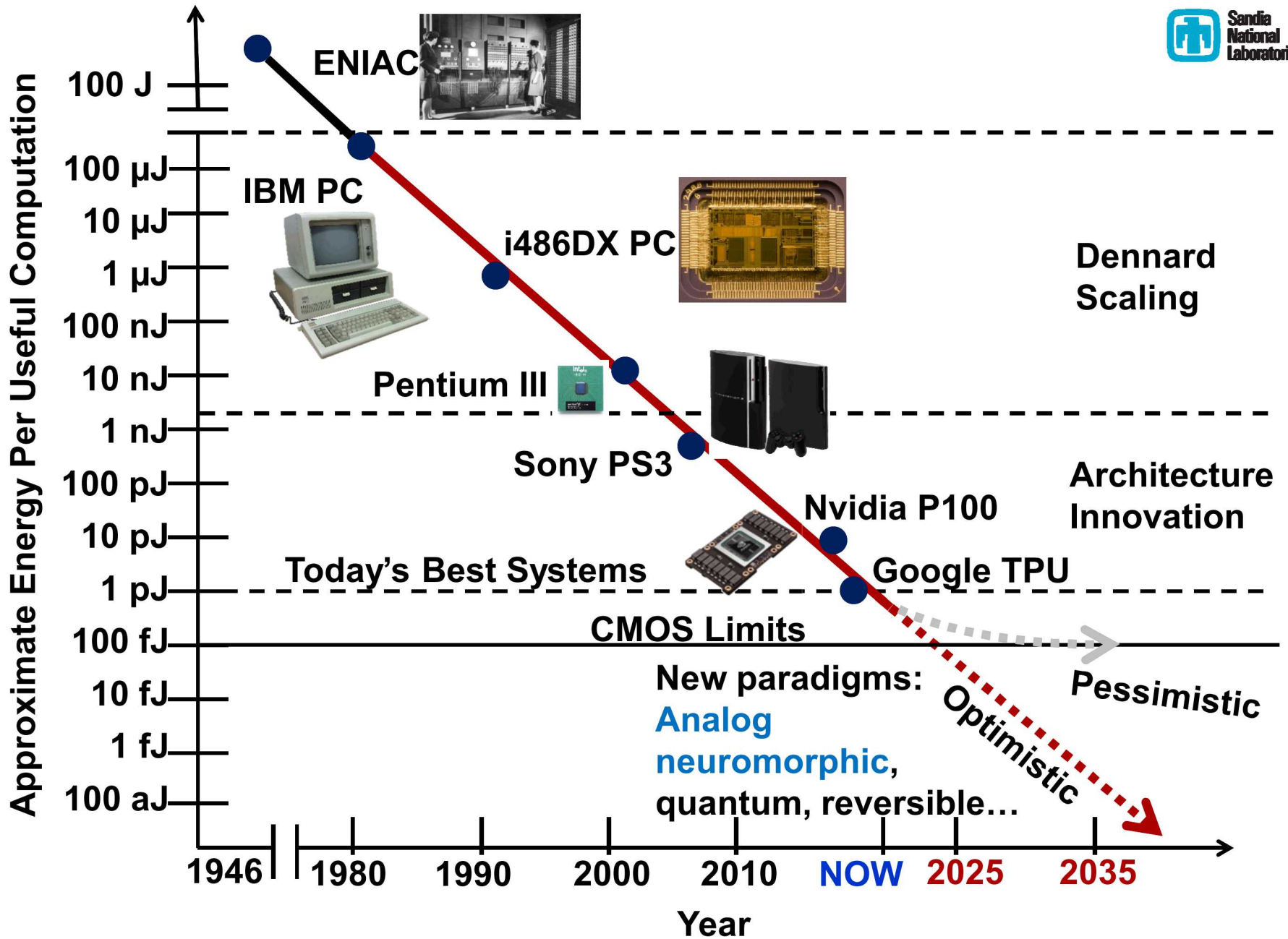
Neuromorphic Computing with Analog Nonvolatile Memory

Matthew J. Marinella
Sandia National Laboratories, Albuquerque, NM

Contributors: S. Agarwal, C. Bennett, R. Jacobs-Gedrim, E. Fuller, A.A. Talin, J.A. Incorvia (UT)



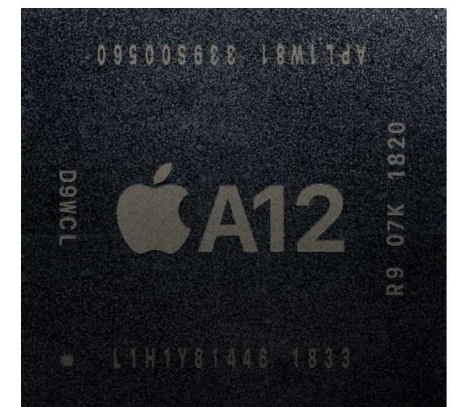
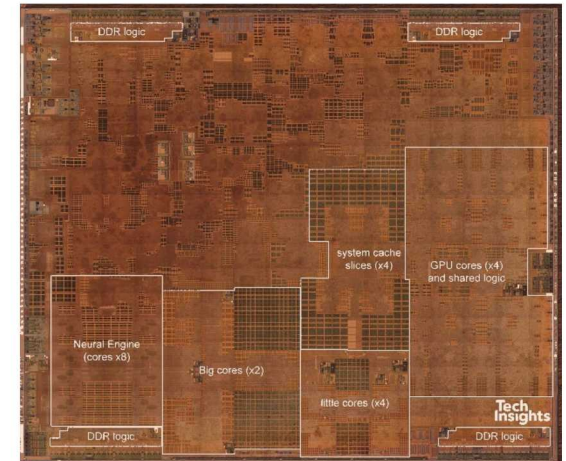
Sandia National Laboratories is a multimission laboratory managed and operated by National Technology and Engineering Solutions of Sandia LLC, a wholly owned subsidiary of Honeywell International Inc., for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-NA0003525.



State of the Art: Apple A12



- Apple's iPhone X main SoC processor
 - 7nm TSMC process
- Includes “neural engine” accelerator IP
 - Apple spec: 5 TeraOps/s (8 bit)
 - Power is $\sim 2.5\text{-}5\text{W}$
 - Hence, $\sim 1\text{-}2\text{ TeraOp/W}$,
- **State of the art neural accelerator is about 500fJ to 1pJ per 8 bit operation**
 - Nearing digital limits?
- Similar for published accelerator data, modern GPU, and Google TPU



apple.com, techinsights.com

Analog Computation with a Resistive Switch Crossbar

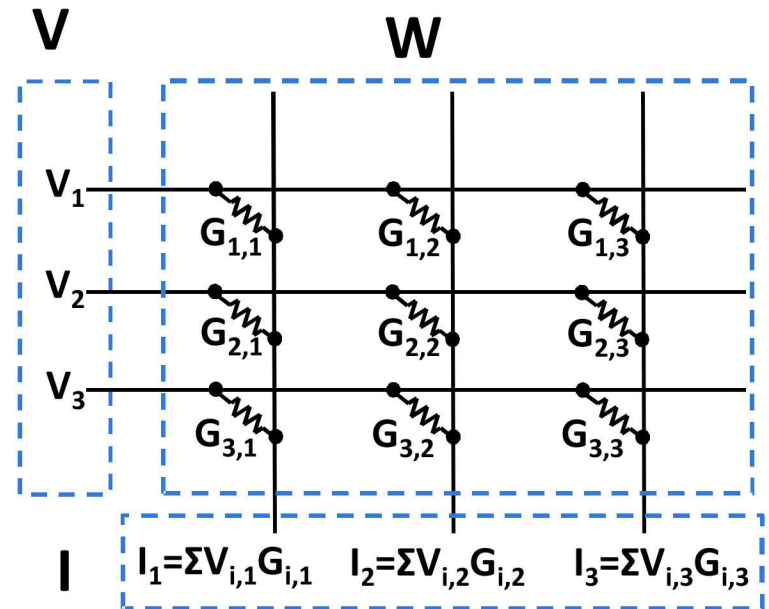
- Electronic Vector Matrix Multiply

Mathematical

$$V^T W = I$$

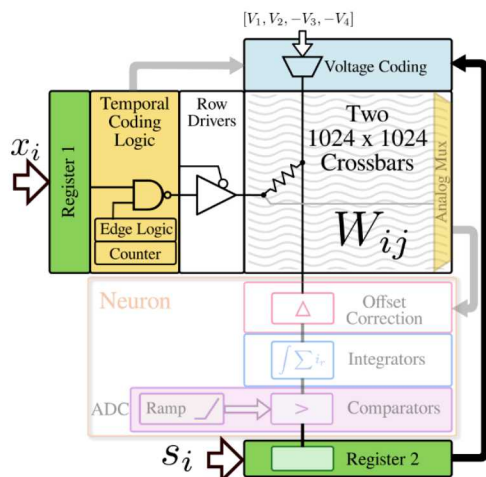
$$\begin{bmatrix} V_1 & V_2 & V_3 \end{bmatrix} \begin{bmatrix} W_{1,1} & W_{1,2} & W_{1,3} \\ W_{2,1} & W_{2,2} & W_{2,3} \\ W_{3,1} & W_{3,2} & W_{3,3} \end{bmatrix} = \begin{bmatrix} I_1 = \sum V_{i,1} W_{i,1} & I_2 = \sum V_{i,2} W_{i,2} & I_3 = \sum V_{i,3} W_{i,3} \end{bmatrix}$$

Electrical



Let the physics do the computing

Matrix Energy/Latency Analysis



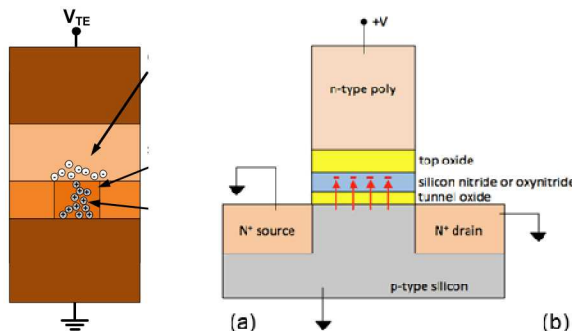
Marinella, et al, *IEEE JETCAS*, 2018

Component	Vector Matrix Multiply	Matrix Vector Multiply	Outer Product Update
Energy/Op IFG (fJ)	11.9	11.9	0.2
Energy/Op ReRAM (fJ)	12.2	12.2	2.1
Energy/Op SONOS (fJ)	13.7	13.7	68.2
Energy/Op SRAM (fJ)	2718	4630	4102
Array Latency IFG (μ s)	0.39	0.39	1.9
Array Latency ReRAM (μ s)	0.38	0.38	0.51
Array Latency SONOS (μ s)	0.40	0.40	20
Array Latency SRAM (μ s)	4	32	8

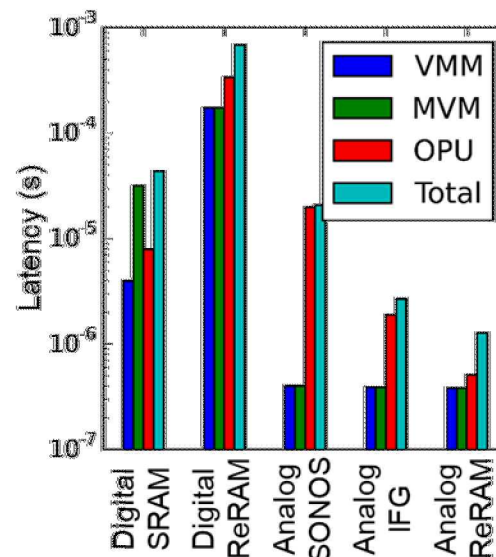
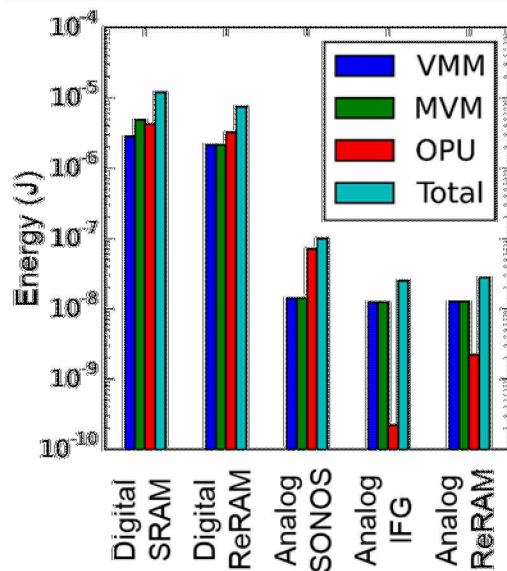
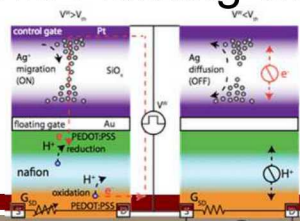
<2 fJ/op

OxRAM

SONOS



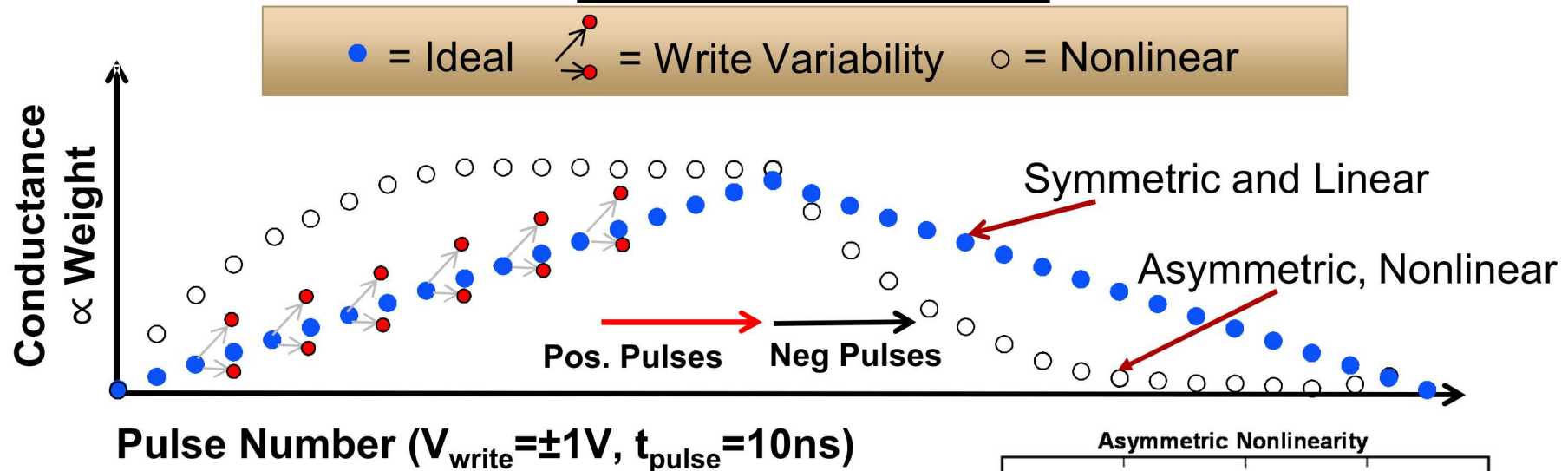
Ionic Floating Gate



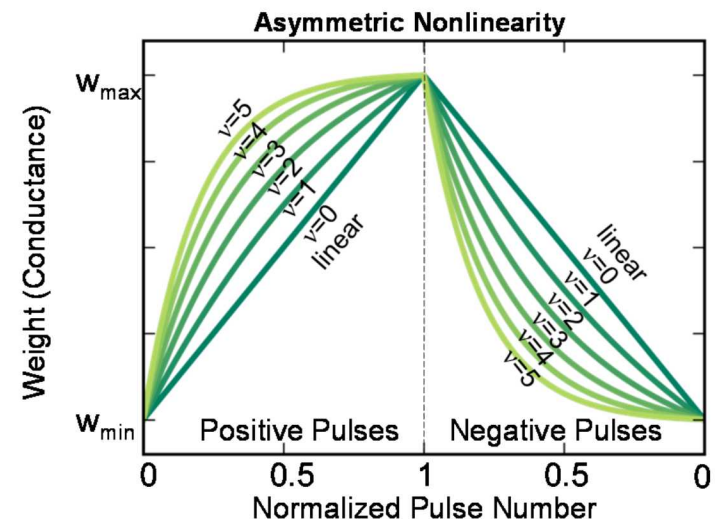
Will enable training at the edge!

Analog Device Requirements

Conductance versus Pulse

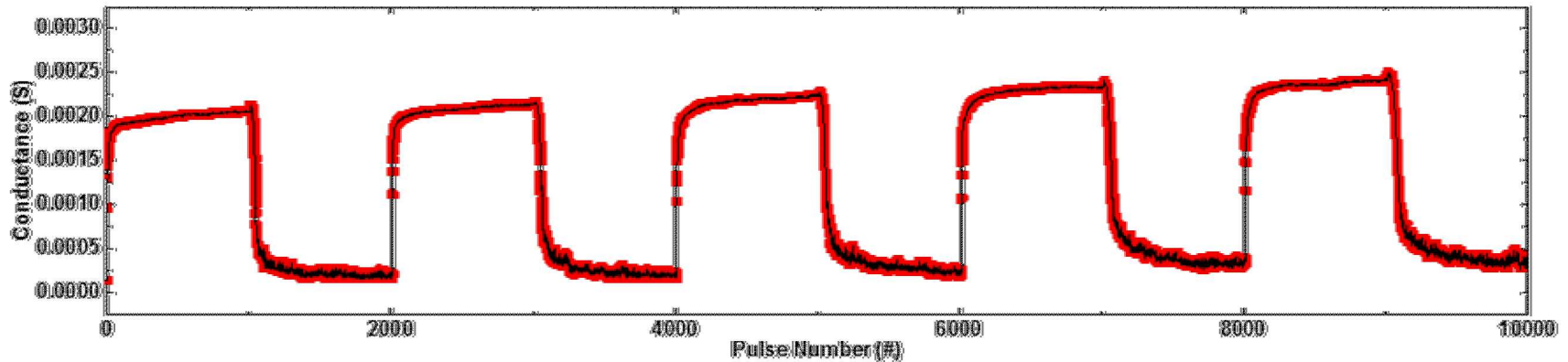


Read Noise σ (% Range)	5%
Write Noise σ (% Range)	0.4%
Asymmetric Nonlinearity (v)	0.1
Symmetric Nonlinearity (v)	5
Maximum Current	13 nA
Minimum Retention (@ 85°C)	7 days
Minimum Nudge Endurance	10^7

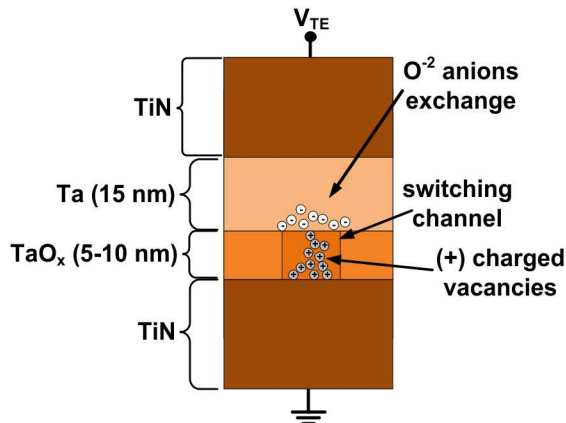


Device-Algorithm Interaction = Strict analog requirements

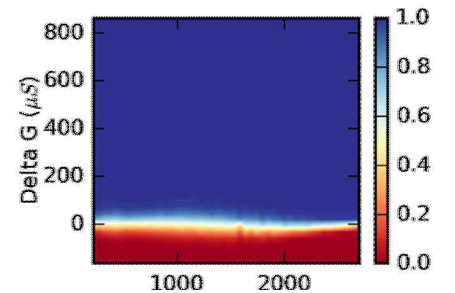
TaOx ReRAM Training Evaluation



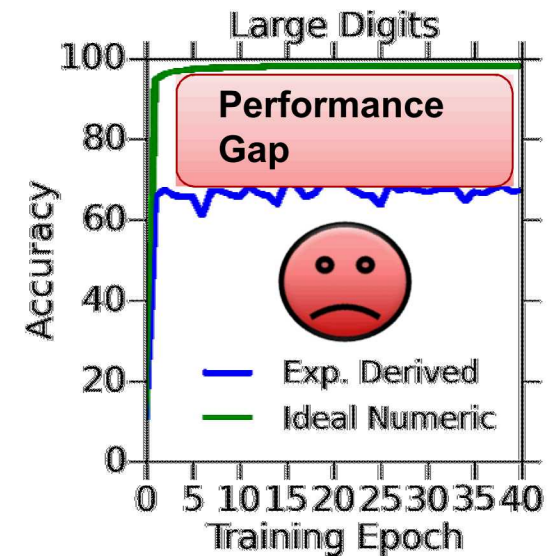
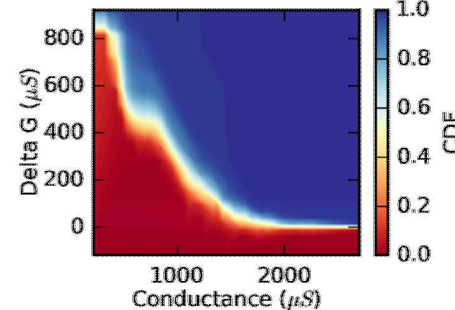
10 ns



RESET

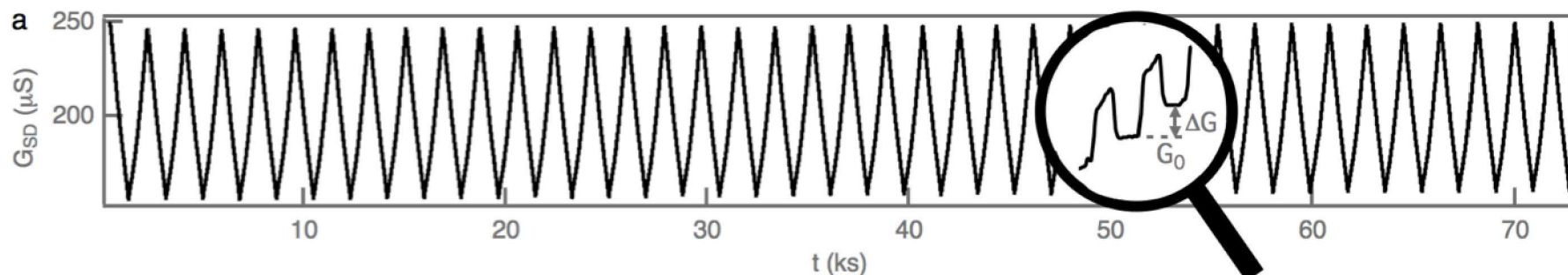


SET



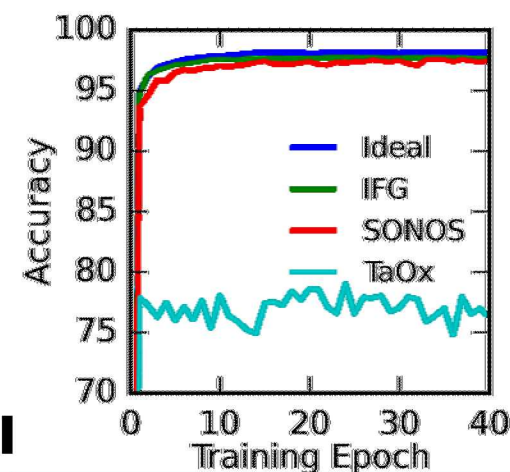
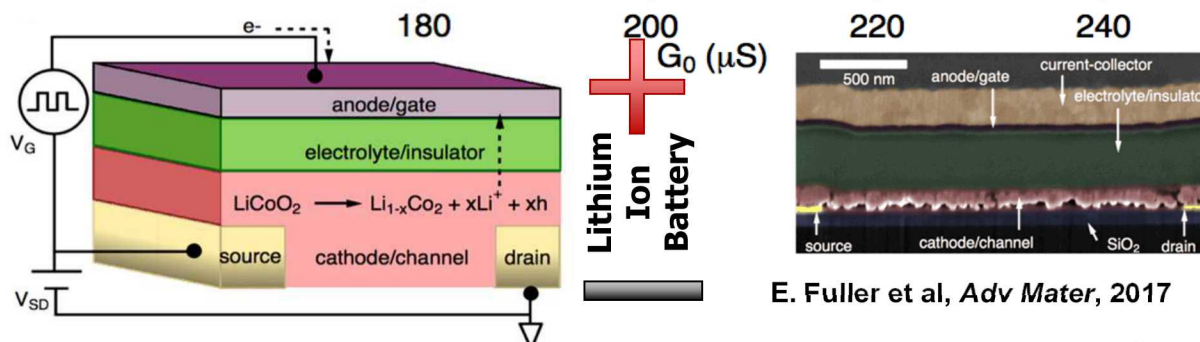
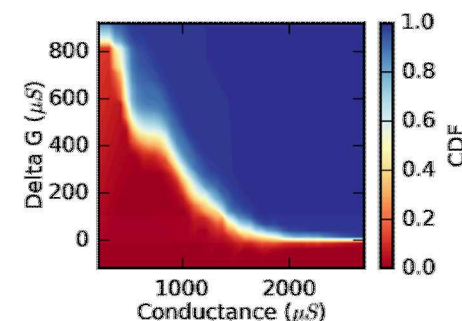
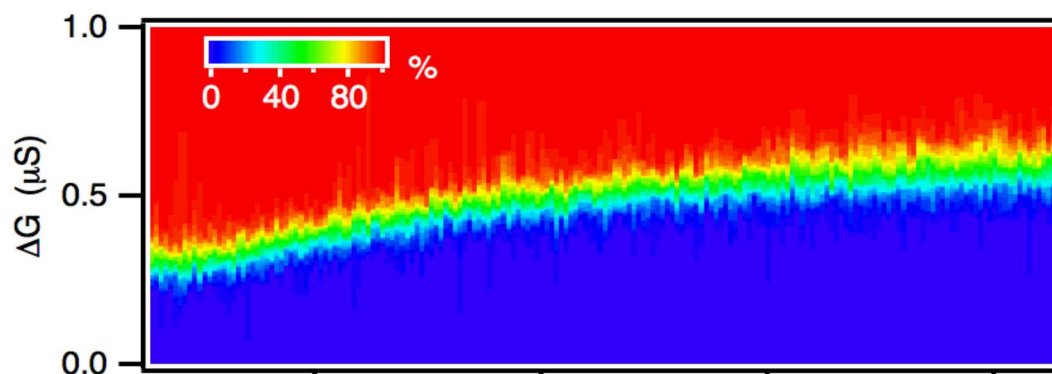
OxRAM does not meet analog training accelerator requirements

Ionic Transistor



LISTA > 200 states

TaOx ReRAM



Emerging ionic devices show promise for anal

Key Messages

- Energy efficiency critical at all scales, especially at the edge
- Digital CMOS nearing its limits
- Analog crossbar training operations 10-1000x more efficient than digital CMOS limits
 - This can enable training at the edge
- Training at the edge is desirable
 - Communication bandwidth is limited: cannot send all data to the cloud
 - Privacy: may not want to send all data to the cloud
- Device affects algorithm accuracy → challenge for analog
 - Ideal analog devices a topic of continued research
 - Compatible with algs which tolerate moderate precision

Backup Slides

Acknowledgements

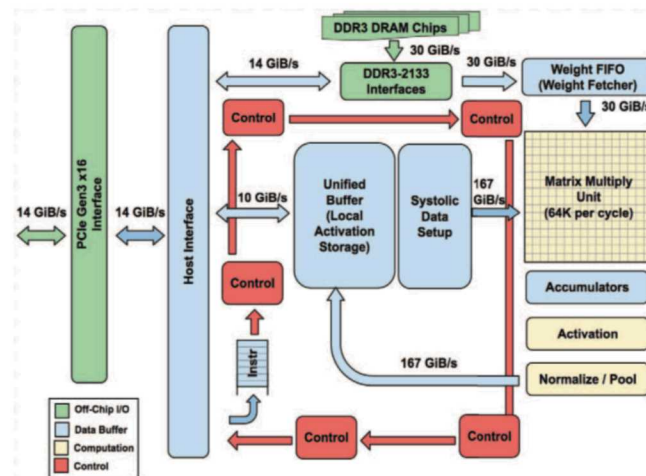
- Funding
 - Sandia National Laboratories Laboratory Directed Research and Development
 - Department of Energy Advanced Manufacturing Office (AMO)
 - Department of the Defense, Defense Threat Reduction Agency under grant no. HDTRA1-11-21-BRCWMD-BAA
- Many collaborators:
 - B. Draper, K. Knisely, M. Van Heukelom, M. King, A. Mitchell, R. McCormick, Sandia
 - D. Barlage, G. Shoute, U. Alberta
 - Alberto Saleo group, Stanford
 - Michael Kozicki, Jennifer Taggart, Sheming Yu, ASU
 - Engin Ipek, Isaac Richter, U Rochester
 - John Paul Strachan, Stan Williams (retired), HPE Labs
 - Jianhua Yang, Qiangfei Xia, U Mass
 - S. Salahuddin, UC Berkeley
 - Tarek Taha, C. U Dayton
 - Paul Franzon, NC State University
 - Dhireesha Kudithipudi, RIT
 - Dozens of others...

Session Charge

- AI/ML has provided an explosion in new applications and features, but at a significant energy cost. Processing at the “edge” which is energy constrained is a unique challenge. What role will “analog” play in the AI/ML processing at the edge?
- What new devices are required for analog in machine learning?
 - Requirements in: precision, retention, linearity, speed etc.?
 - For example, could it be that, in future, you could have larger AI machines artificially produce data for training smaller AI machines?
- How scalable is Analog in Machine Learning?
 - Only for smaller “edge” applications?
 - Only for inference?
 - Learning on the fly?
- What should be the goals for Analog in Machine Learning for the next 3, 6 and 10 years?

State of the Art Digital

- TPU v1 Performance/Watt
 - Die level performance of 2.3 TeraOps/W
 - **→ ~ 1 pJ per 8 bit operation!**
- Intel Haswell die comparison:
 - 18 GigaOps/W
 - → 55 pJ per 8-bit operation
- Similar for mobile processors



Model	Die										Benchmarked Servers				
	mm ²	nm	MHz	TDP	Measured		TOPS/s		GB/s	On-Chip Memory	Dies	DRAM Size	TDP	Measured	
					Idle	Busy	8b	FP						Idle	Busy
Haswell E5-2699 v3	662	22	2300	145W	41W	145W	2.6	1.3	51	51 MiB	2	256 GiB	504W	159W	455W
NVIDIA K80 (2 dies/card)	561	28	560	150W	25W	98W	--	2.8	160	8 MiB	8	256 GiB (host) + 12 GiB x 8	1838W	357W	991W
TPU	<331*	28	700	75W	28W	40W	92	--	34	28 MiB	4	256 GiB (host) + 8 GiB x 4	861W	290W	384W

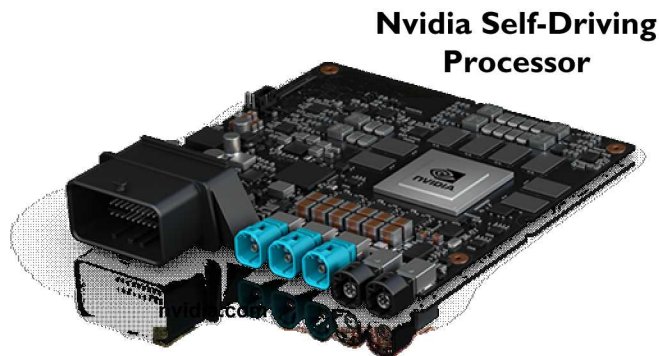
N. P. Jouppi et al, 2017 ACM/IEEE 44th Annual International Symposium on Computer Architecture (ISCA), Toronto, ON, 2017

AI Across Power Envelopes

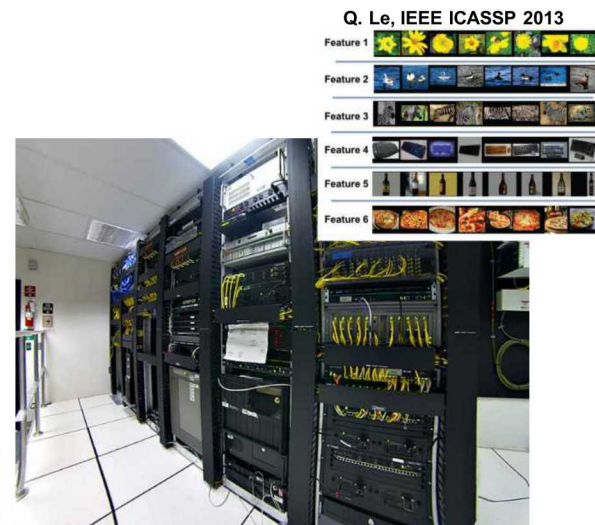
IoT, Edge, and
Mobile
Computing

Self Driving Cars,
Unmanned Aerial
Vehicles, and Satellite
Computing

Datacenters, HPC



wikimedia.org



ASCI Red Supercomputer

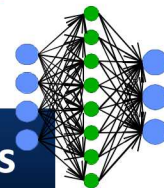
1W 10W 10^2 W 10^3 W 10^4 W 10^5 W 10^6 W

	SONOS	RRAM	PCM	MRAM	FeRAM	Ionic
On/Off ratio	10^6	10 - 10^4	10^2 - 10^4	1.5-2	10^2 - 10^3	10^3
Retention	High	High	High	High	High	Medium
Drift	Weak	Weak	Strong	None	None	None
Endurance	10^6	10^8	10^6	$>10^{12}$	10^{10}	10^9
Switching Energy (Nudge)	100 fJ	100 fJ	10pJ	100fJ	100fJ	<100fJ
Switching Speed	1 μ s	<10ns	10-100ns	<10ns	30ns	<10ns
Analog Tunability	High	Moderate	Low	Low	Low	High
DNN Inference Suitability	High	High	Low	Low	Low	High
DNN Training Suitability	Moderate	Moderate	Low	Low	Low	Moderate to High

Device to Algorithm Model

Target Algorithms

- Deep Neural Nets
- Convolutional NN



Algorithms

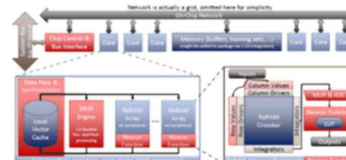
Architecture

Circuits

Devices

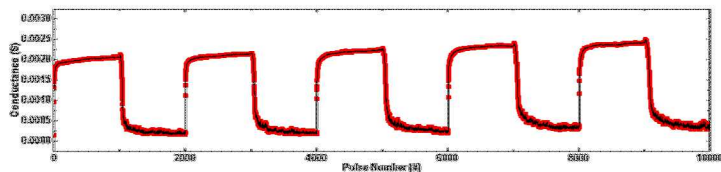
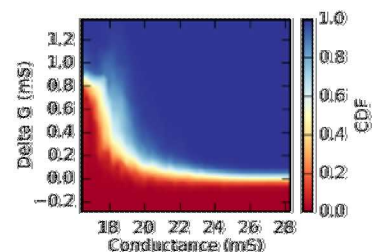
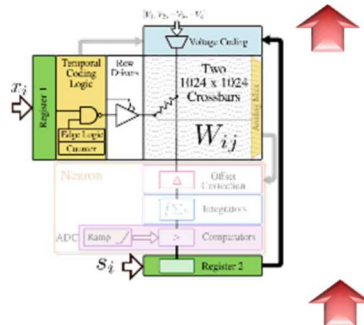
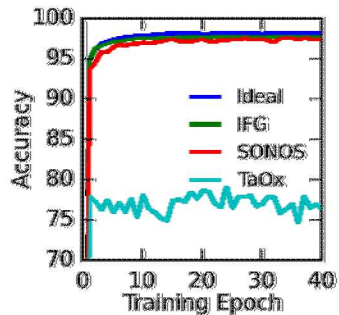
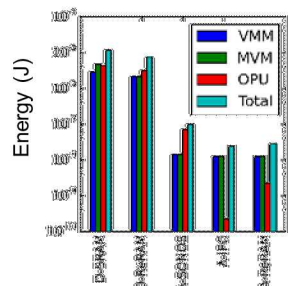
Energy/Performance Model

Model performance and energy requirements

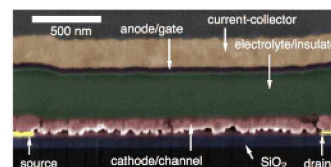
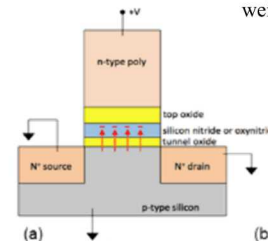
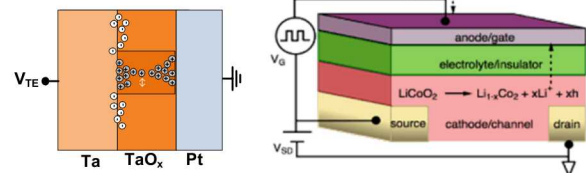


ROSS SIM

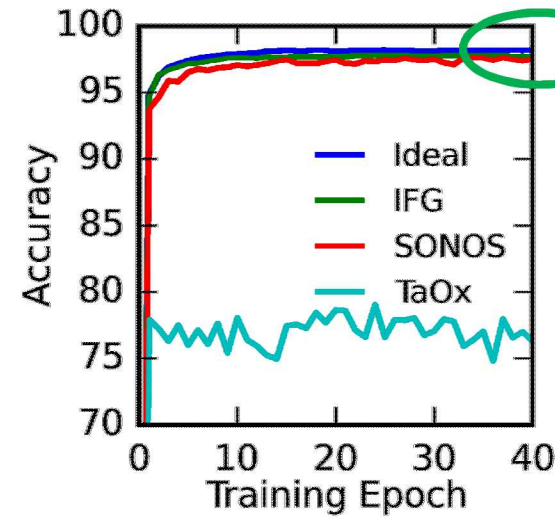
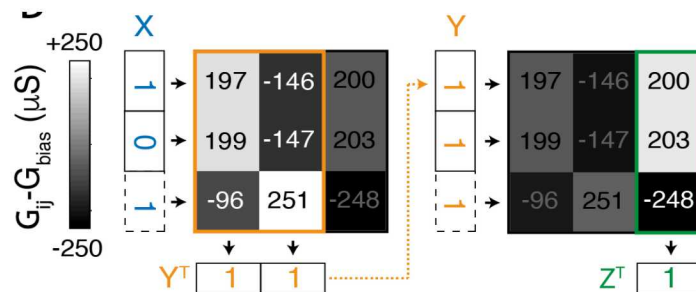
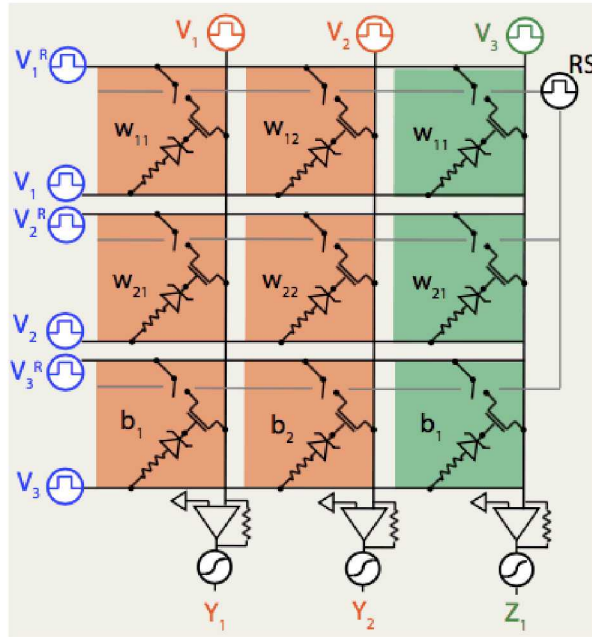
Translates device measurements and crossbar circuits to algorithm-level performance



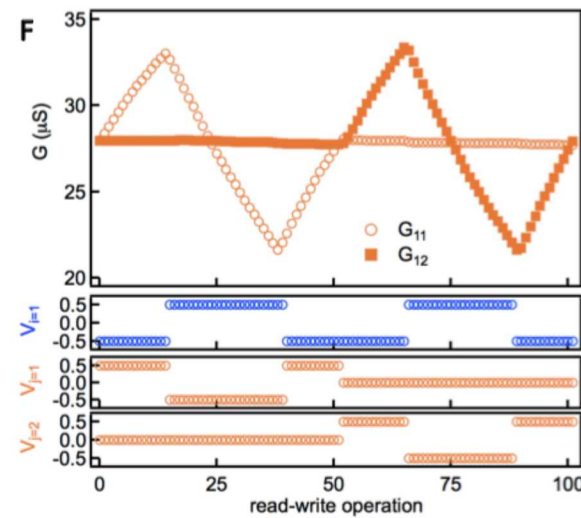
Analog characterization



IFG Array Demonstration

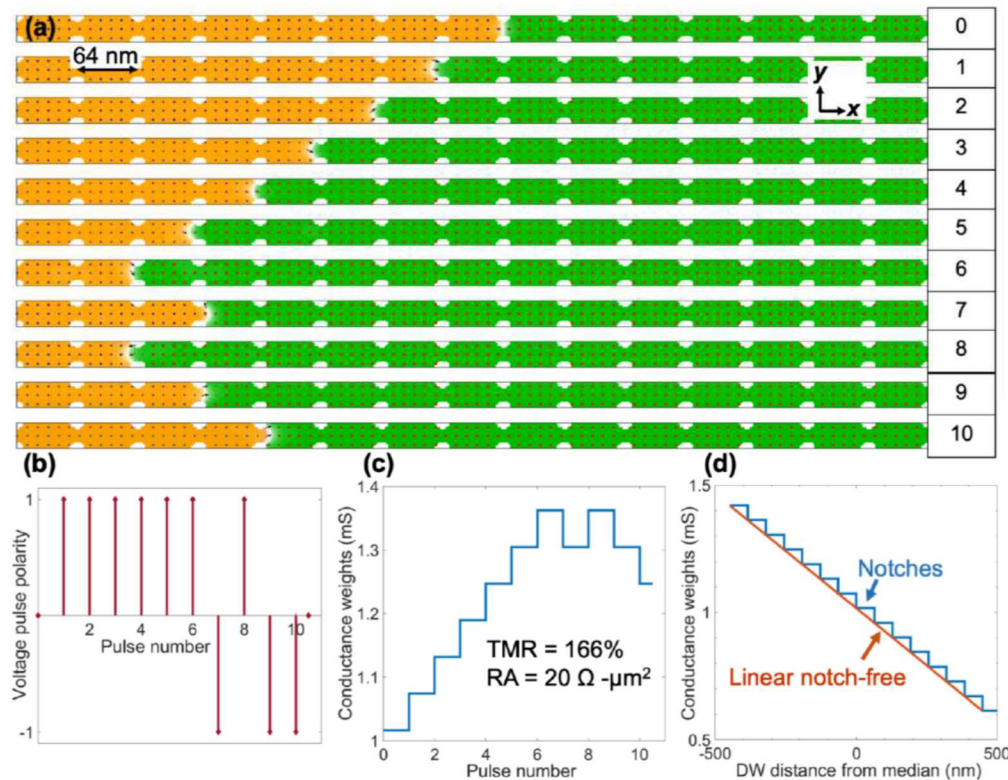
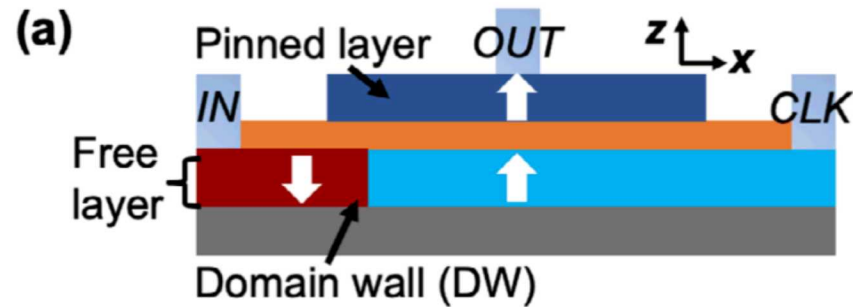


Near ideal accuracy



E. J. Fuller, S. T. Keene, A. Melianas, Z. Wang, S. Agarwal, Y. Li, Y. Tuchman, C. D. James, M. J. Marinella, J. J. Yang, A. Salleo, A. A. Talin, *Science* 364, 570, (2019).

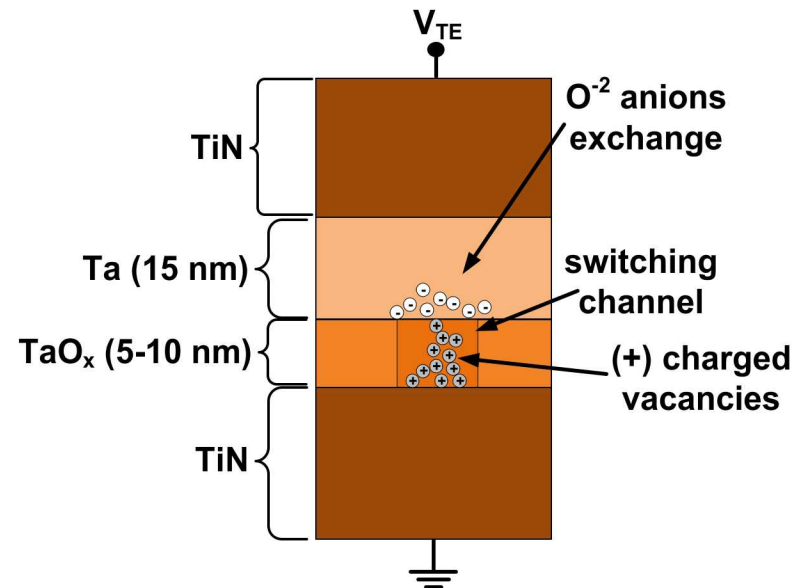
Magnetic Synapse Concept



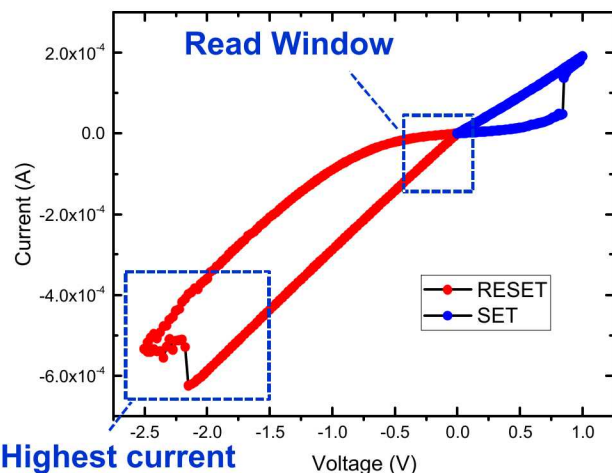
Exemplar Synapse: Oxide ReRAM

ReRAM (OxRAM)

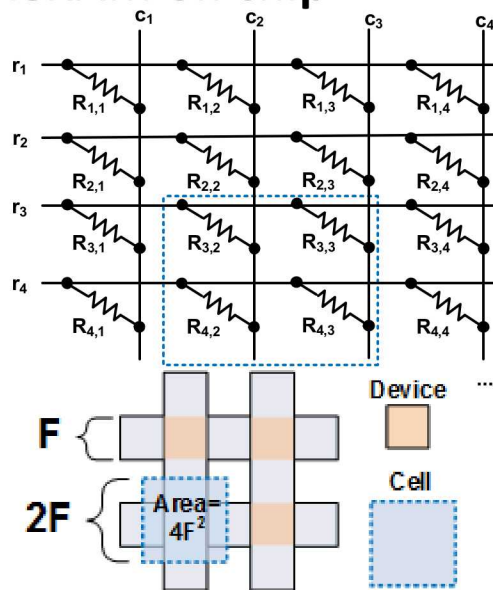
- Starts as insulating MIM structure
- Forming: remove $O^{2-} \rightarrow$ soft breakdown
- Bipolar resistance modulation
- Excellent memory attributes: Switching in less than 1ns, less than 1 pJ demonstrated, scaling to 5nm, $>10^{12}$ write cycles possible
- Potential for 100 Tbit of ReRAM on chip



SET-RESET

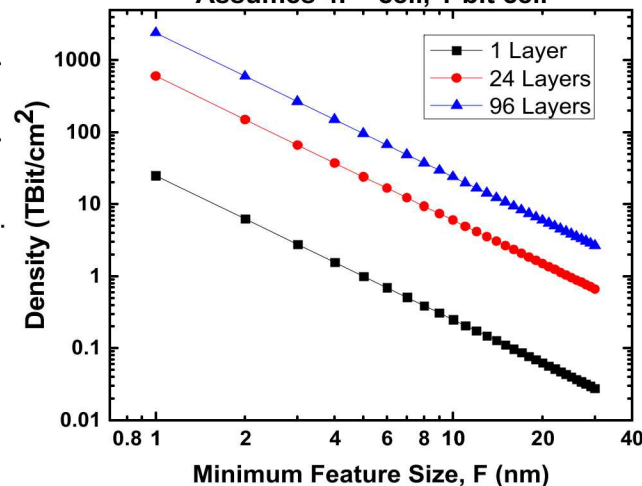


Highest current switching process



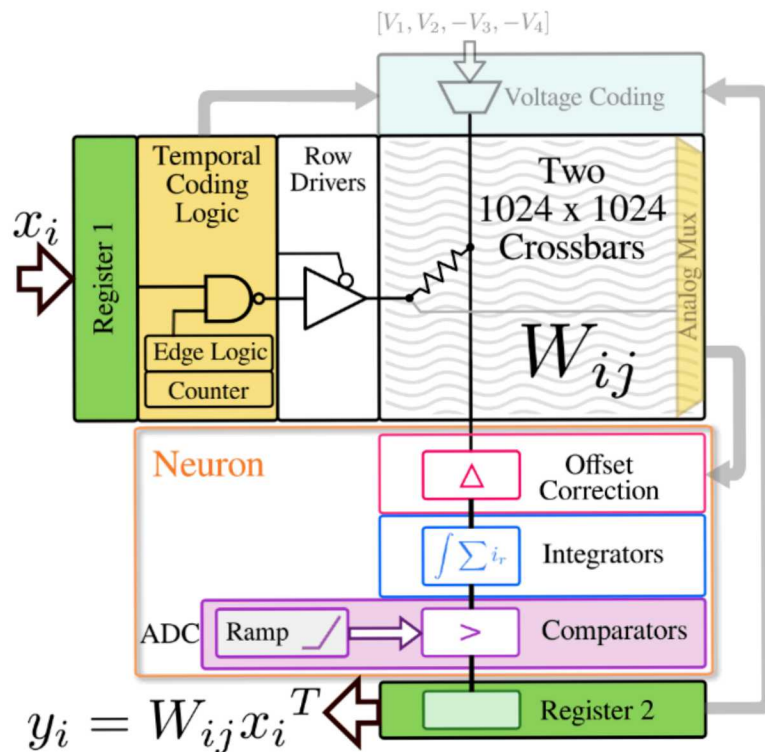
ReRAM Density vs Min. Feature Size

Assumes $4F^2$ cell, 1-bit cell

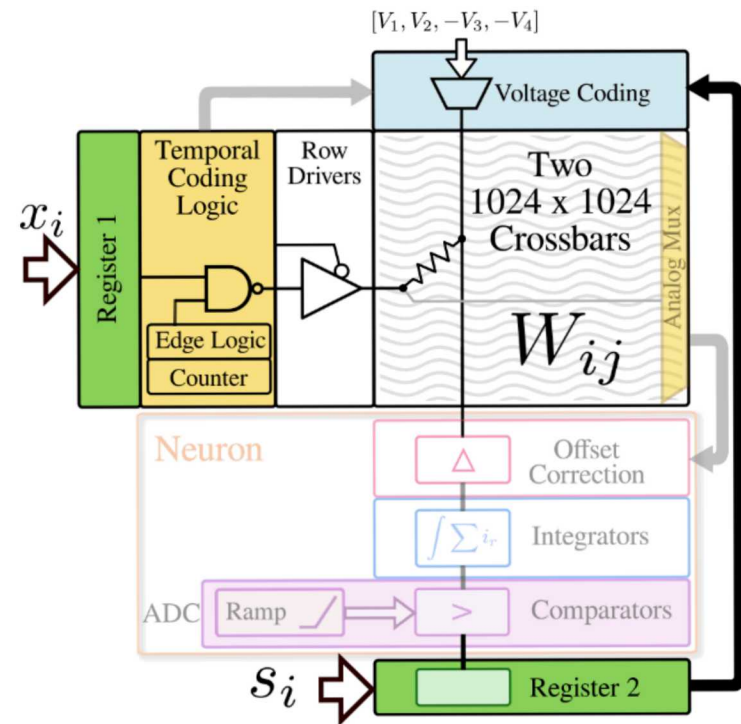


Key Circuit Block/Kernel Analysis

Vector Matrix Multiply (Classification)

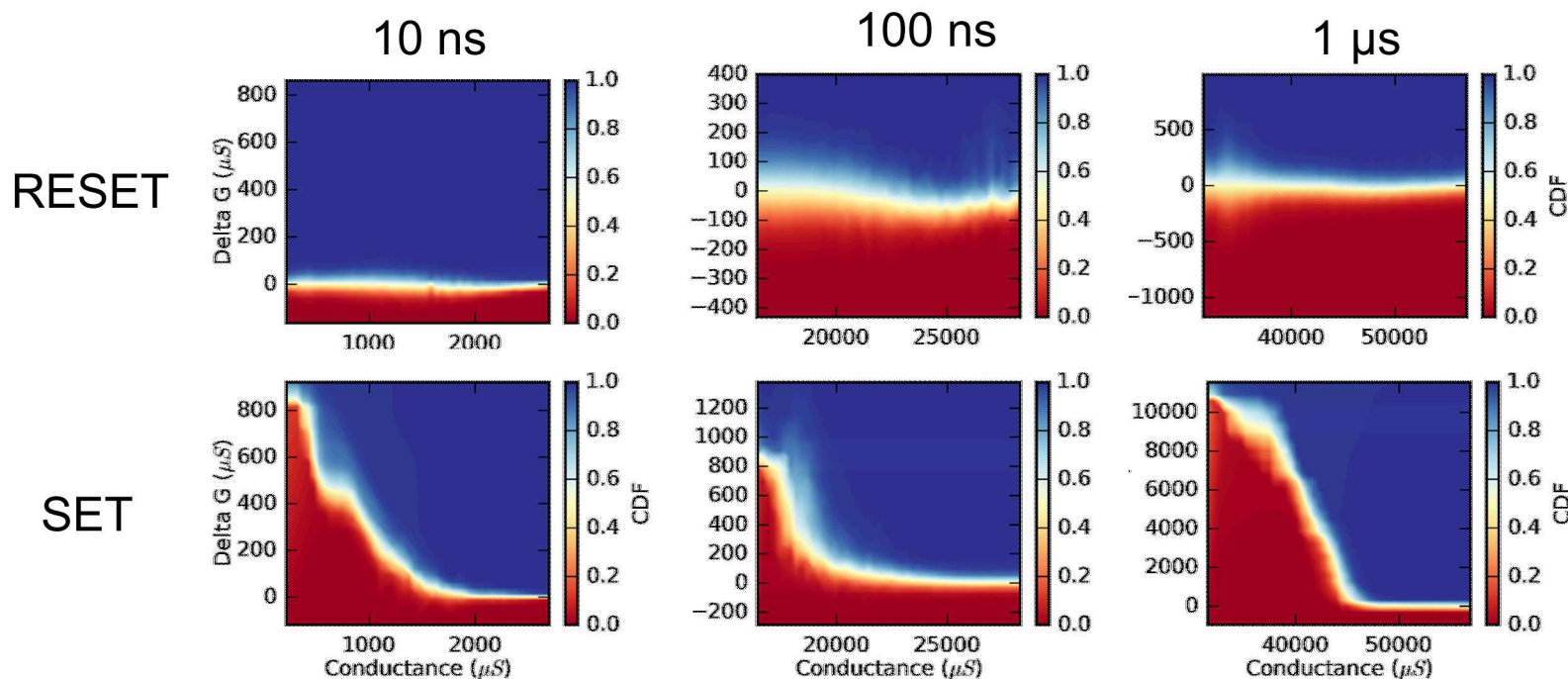
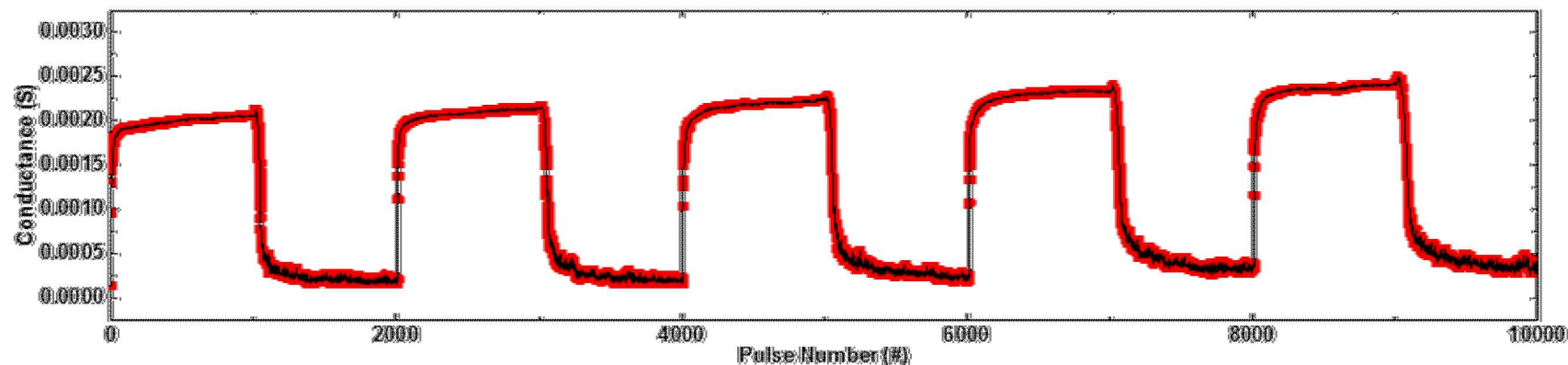


Rank-1 Update (Training)

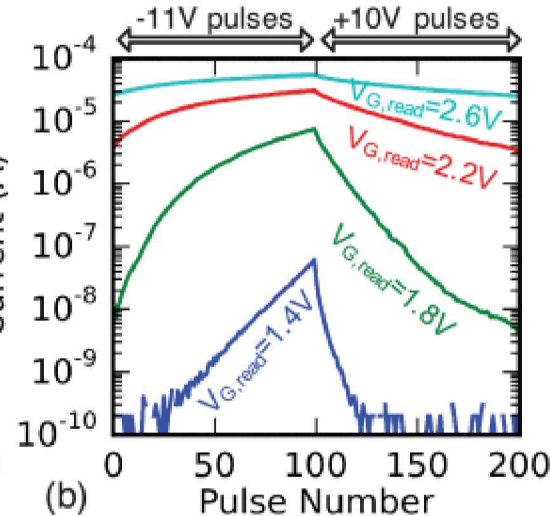
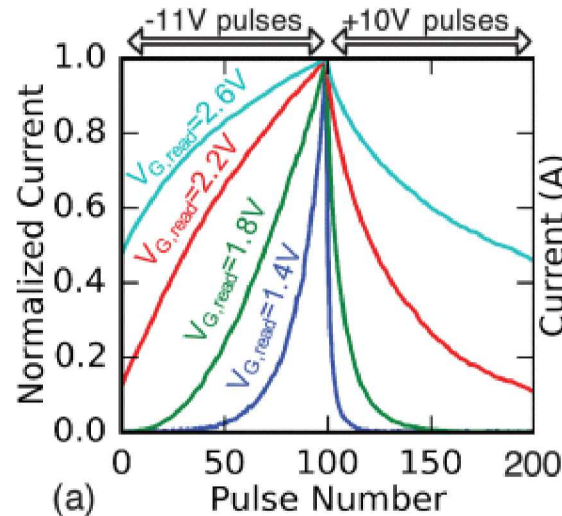
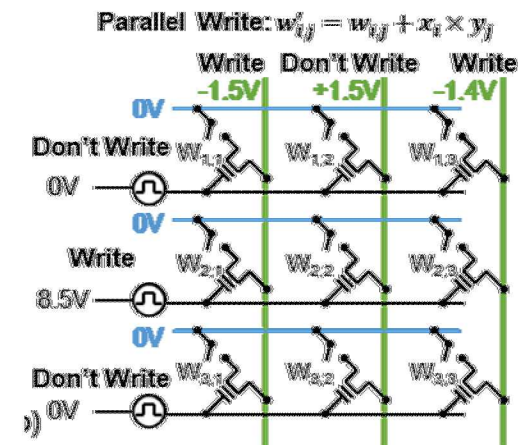
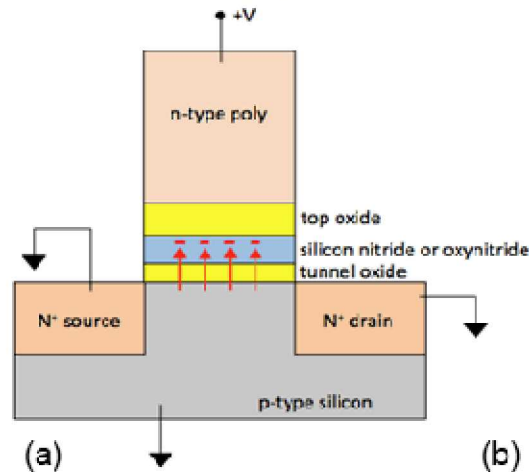


Marinella, Agarwal, et al, *IEEE JETCAS*, 2018

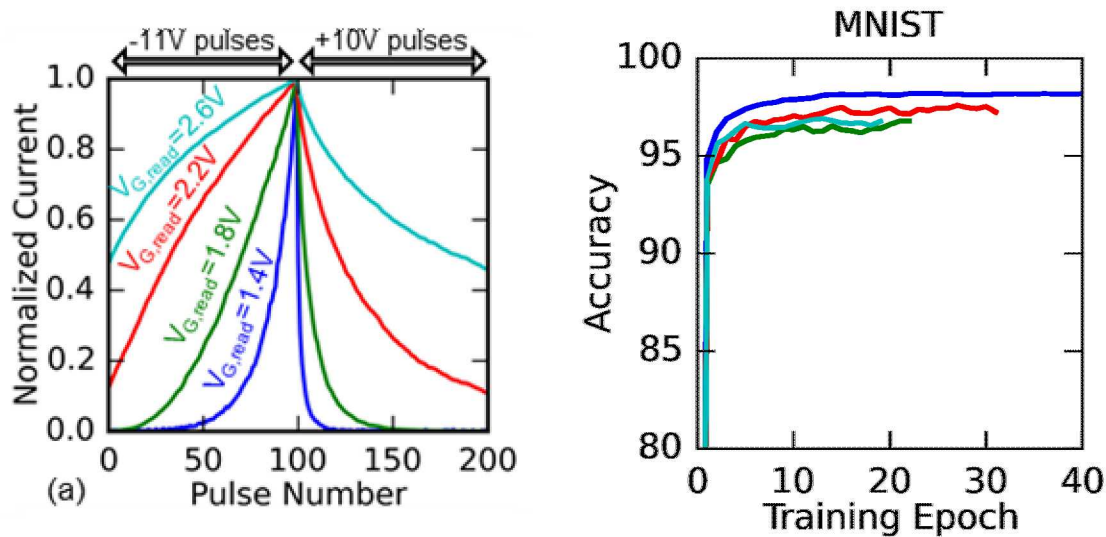
Lookup Table Generation



Semiconductor-Oxide-Nitride-Oxide-Semiconductor (SONOS)



SONOS Accuracy and Energy



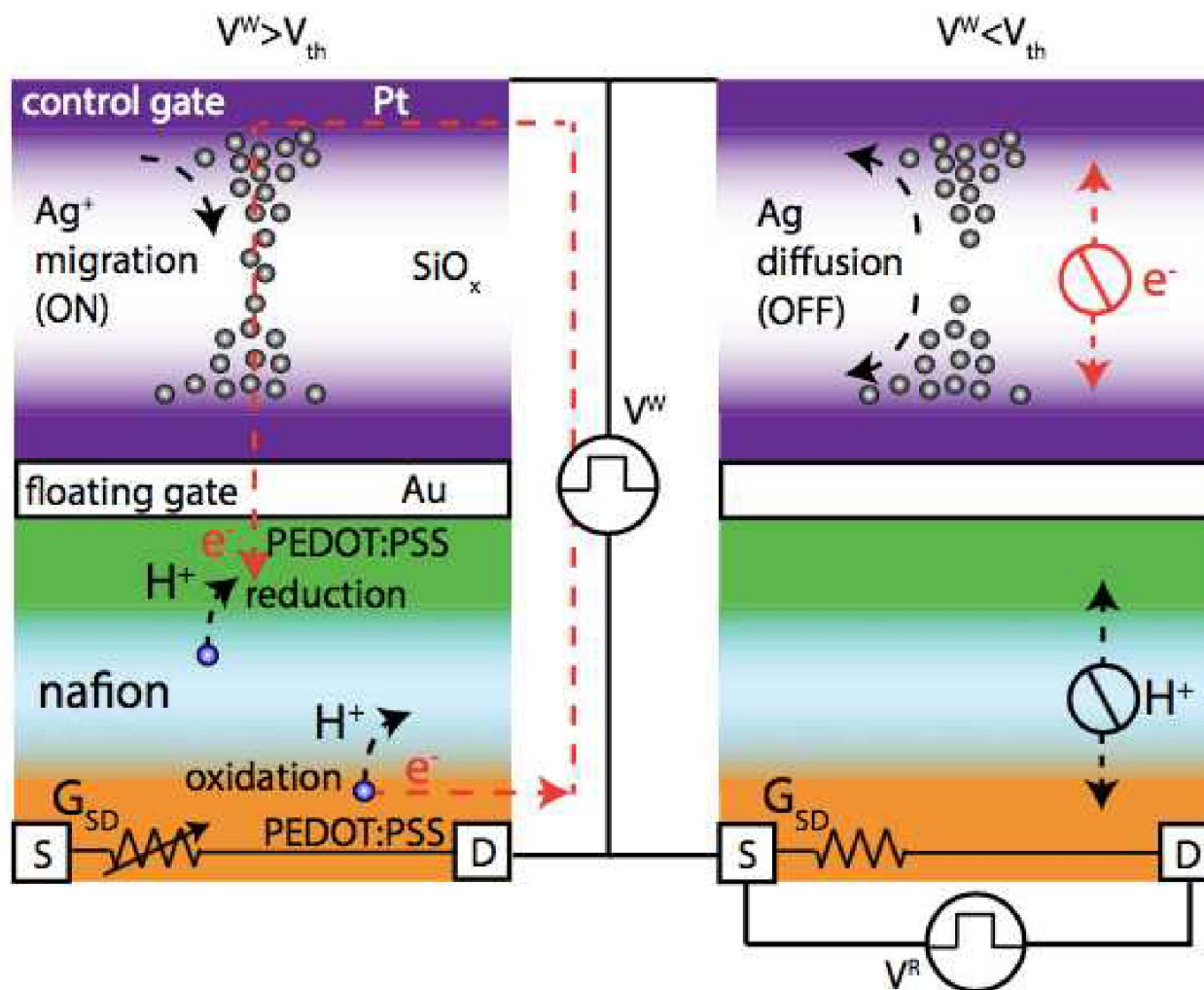
Component	Vector Matrix Multiply	Matrix Vector Multiply	Outer Product Update
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Energy/Op SRAM (fJ)	2718	4630	4102
Array Latency ReRAM (μs)	0.38	0.38	0.51
Array Latency SONOS (μs)	0.40	0.40	20
Array Latency SRAM (μs)	4	32	8

Low
inference
energy

Slow
write

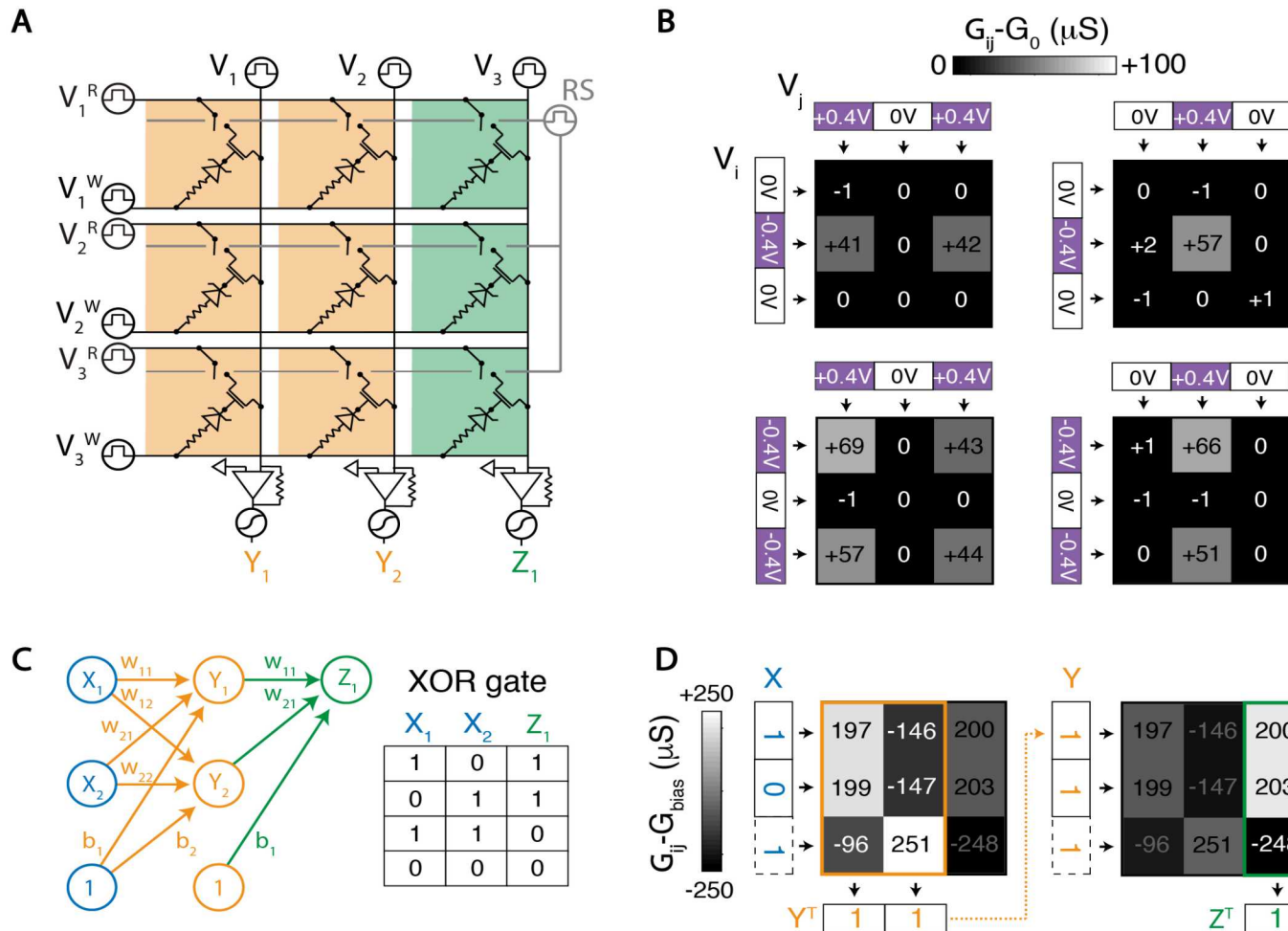
S Agarwal et al, IEEE J Exploratory Solid-State Computational Devices and Circuits, 2019.

Ionic Floating Gate



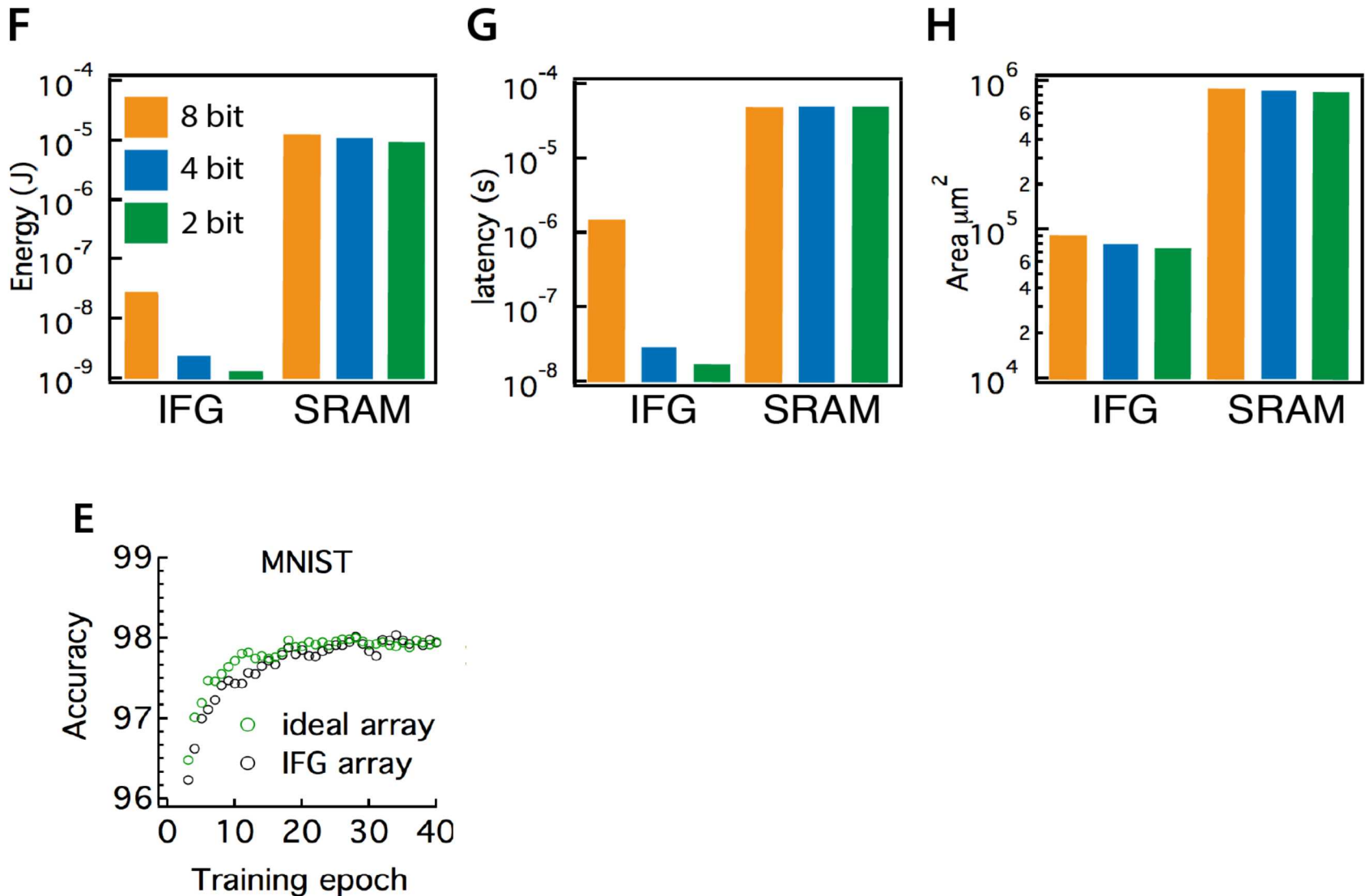
E. J. Fuller, S. T. Keene, A. Melianas, Z. Wang, S. Agarwal, Y. Li, Y. Tuchman, C. D. James, M. J. Marinella, J. J. Yang, A. Salleo, A. A. Talin, *Science* 364, 570, (2019).

Programming Demonstration

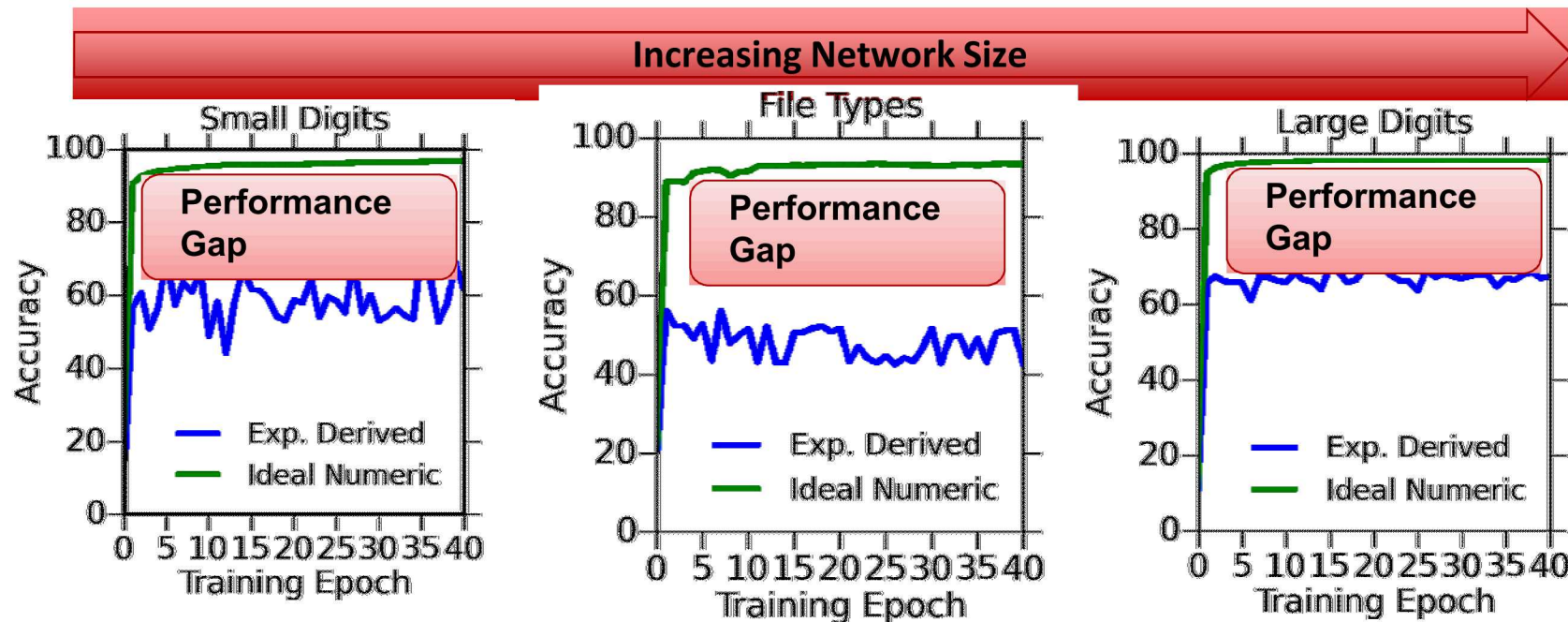


E. J. Fuller, S. T. Keene, A. Melianas, Z. Wang, S. Agarwal, Y. Li, Y. Tuchman, C. D. James, M. J. Marinella, J. J. Yang, A. Salleo, A. A. Talin, *Science* 364, 570, (2019).

Programming Demonstration



CrossSim Model of TaOx ReRAM: MNIST, Backprop Training

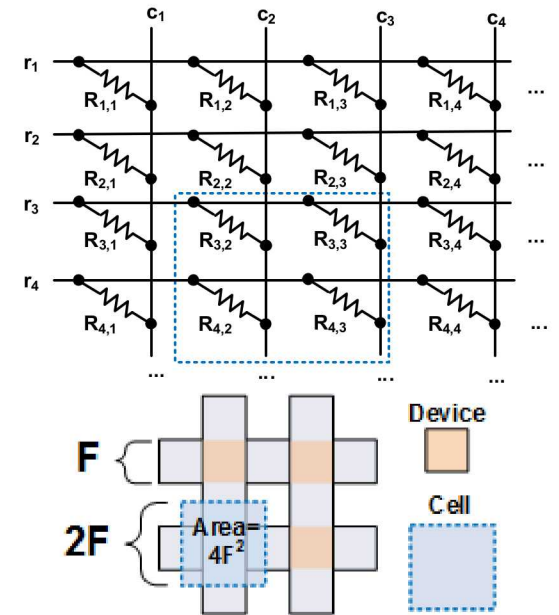


Data set	# Training Examples	# Test Examples	Network Size
UCI Small Digits[1]	3,823	1,797	64×36×10
File Types[2]	4,501	900	256×512×9
MNIST Large Digits[3]	60,000	10,000	784×300×10

CROSS SIM

Crossbar Theoretical Limits

- Potential for 100 Tbit of ReRAM on chip
- If each can perform 1M computations of interest per second (1 M-op):
 - 10^{12} active devices/chip x 10^6 cycle per second $\rightarrow 10^{18}$ comps per second per chip
 - Exascale-computations per sec on one chip!
- In order to not melt the chip, entire area must be limited to $\sim 100\text{W}$
- Allowed energy per operation = $P \times t/\text{op}$
 $= 100\text{W} / 10^{18} = 10^{-16} = 100 \text{ aJ}/\text{operation}$
- 10nm line capacitance = 10 aF
- Can charge line to 1V with **10 aJ**
- Drawback: “only” $\sim 100\text{B}$ transistors/chip



ReRAM Density vs Min. Feature Size

Assumes $4F^2$ cell, 1-bit cell

